## **AMENDMENTS TO THE CLAIMS**

- (Currently Amended) An apparatus comprising:

   a plurality of devices formed on a substrate and in a process condition to be singulated;

   and

   a scribe line area separating each of the plurality of devices; and
   a masking material overlying a portion of the scribe line area.
- 2. (Original) The apparatus of claim 1, wherein the masking material is transparent.
- 3. (Original) The apparatus of claim 1, wherein the masking material comprises an acrylate moiety.
- 4. (Original) The apparatus of claim 1, wherein the masking material has a thickness similar to the thickness of a device portion.
- 5. (Original) The apparatus of claim 1, wherein the plurality of devices comprise as one material layer a material comprising one of a colorant.
- 6. (Original) The apparatus of claim 5, wherein the colorant comprises a pigment.
- 7. (Original) The apparatus of claim 1, wherein the plurality of devices each comprise a sensor portion.
- 8. (Original) The apparatus of claim 1, wherein the masking material overlies the entire portion of the scribe line area adjacent the plurality of devices.
- 9. (Original) The apparatus of claim 6, wherein the masking material comprises a plurality of discrete structures occupying less than the entire portion of the scribe line area adjacent the plurality of devices.

- 10. (Currently Amended) A semiconductor wafer comprising:
- a plurality of <u>devices integrated circuits</u> formed on the wafer, each integrated circuit mapped on the surface of a wafer adjacent a scribe line area <u>and in a process condition to be singulated</u>; and
  - a masking material overlying a portion of the scribe line area.
- 11. (Original) The semiconductor wafer of claim 10, wherein the masking material is transparent.
- 12. (Original) The semiconductor wafer of claim 10, wherein the masking material has a thickness similar to the thickness of a device portion.
- 13. (Original) The semiconductor wafer of claim 4, wherein the plurality of integrated circuits comprise as one material layer, a material comprising one of a colorant.
- 14. (Original) The semiconductor wafer of claim 13, wherein the colorant comprises a pigment.
- 15. (Original) The semiconductor wafer of claim 10, wherein the plurality of devices comprise a sensor portion.
- 16. (Original) The semiconductor wafer of claim 10, wherein the masking material overlies the entire portion of the scribe line area adjacent the plurality of devices.
- 17. (Original) The semiconductor wafer of claim 10, wherein the masking material comprises a plurality of discrete structures occupying less than the entire portion of the scribe line area adjacent the plurality of devices.